# International Rectifier

# IRF3710S/L

### HEXFET® Power MOSFET

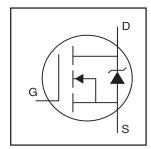
- Advanced Process Technology
- Surface Mount (IRF3710S)
- Low-profile through-hole (IRF3710L)
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

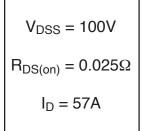
**Description** 

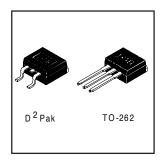
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The  $D^2Pak$  is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible onresistance in any existing surface mount package. The  $D^2Pak$  is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF3710L) is available for low-profile applications.







#### **Absolute Maximum Ratings**

		_	
	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>⑤</sup>	57	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>⑤</sup>	40	A
I <sub>DM</sub>	Pulsed Drain Current ①⑤	180	
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation	3.8	W
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy@\$	530	mJ
I <sub>AR</sub>	Avalanche Current①	28	A
E <sub>AR</sub>	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt 3 \$	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	00.044
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mounted, steady-state)**		40	°C/W

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

· ·		`			'	
Parameter	Min.	Тур.	Max.	Units	Conditions	
Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$	
Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>⑤</sup>	
Static Drain-to-Source On-Resistance			0.025	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 28A ④	
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Forward Transconductance	20			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 28A <sup>⑤</sup>	
Drain-to-Source Leakage Current			25	Λ	$V_{DS} = 100V, V_{GS} = 0V$	
Brain to Godine Edakage Garrent			250	μΛ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$	
Gate-to-Source Forward Leakage			100	nΛ	V <sub>GS</sub> = 20V	
Gate-to-Source Reverse Leakage			-100	IIA I	V <sub>GS</sub> = -20V	
Total Gate Charge			190		I <sub>D</sub> = 28A	
Gate-to-Source Charge			26	nC	$V_{DS} = 80V$	
Gate-to-Drain ("Miller") Charge			82		$V_{GS}$ = 10V, See Fig. 6 and 13 $\oplus$ $\odot$	
Turn-On Delay Time		14			$V_{DD} = 50V$	
Rise Time		59		no	$I_D = 28A$	
Turn-Off Delay Time		58		ns	$R_G = 2.5\Omega$	
Fall Time		48			$R_D = 1.7\Omega$ , See Fig. 10 $\oplus$ $\odot$	
Internal Source Inductance		7.5		nН	Between lead,	
				11111	and center of die contact	
Input Capacitance		3000			$V_{GS} = 0V$	
Output Capacitance		640		pF	$V_{DS} = 25V$	
Reverse Transfer Capacitance		330			f = 1.0MHz, See Fig. 5©	
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Source Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Source Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Source Inductance  Input Capacitance  ———————————————————————————————————	Drain-to-Source Breakdown Voltage         100         —           Breakdown Voltage Temp. Coefficient         —         0.12           Static Drain-to-Source On-Resistance         —         —           Gate Threshold Voltage         2.0         —           Forward Transconductance         20         —           Drain-to-Source Leakage Current         —         —           Gate-to-Source Forward Leakage         —         —           Gate-to-Source Reverse Leakage         —         —           Total Gate Charge         —         —           Gate-to-Source Charge         —         —           Gate-to-Drain ("Miller") Charge         —         —           Turn-On Delay Time         —         14           Rise Time         —         59           Turn-Off Delay Time         —         58           Fall Time         —         48           Internal Source Inductance         —         7.5           Input Capacitance         —         640	Drain-to-Source Breakdown Voltage         100         —         —           Breakdown Voltage Temp. Coefficient         —         0.12         —           Static Drain-to-Source On-Resistance         —         0.025           Gate Threshold Voltage         2.0         —         4.0           Forward Transconductance         20         —         —           Drain-to-Source Leakage Current         —         25         —         —           Gate-to-Source Leakage Current         —         100         —         —         250           Gate-to-Source Forward Leakage         —         —         100         —         —         —         100           Gate-to-Source Reverse Leakage         —         —         190         —         —         —         26           Gate-to-Source Charge         —         —         26         —         —         26           Gate-to-Drain ("Miller") Charge         —         —         82           Turn-On Delay Time         —         14         —           Rise Time         —         59         —           Turn-Off Delay Time         —         58         —           Fall Time         —         48	Drain-to-Source Breakdown Voltage         100         —         V           Breakdown Voltage Temp. Coefficient         —         0.12         —         V/°C           Static Drain-to-Source On-Resistance         —         —         0.025         Ω           Gate Threshold Voltage         2.0         —         4.0         V           Forward Transconductance         20         —         S           Drain-to-Source Leakage Current         —         25         μA           Gate-to-Source Leakage Current         —         250         μA           Gate-to-Source Forward Leakage         —         -100         nA           Gate-to-Source Reverse Leakage         —         -100         nA           Total Gate Charge         —         190         nC           Gate-to-Source Charge         —         26         nC           Gate-to-Drain ("Miller") Charge         —         82           Turn-On Delay Time         —         14         —           Rise Time         —         59         —           Turn-Off Delay Time         —         58         —           Fall Time         —         48         —           Internal Source Inductance         —	

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current		- 57		MOSFET symbol		
	(Body Diode)				showing the		
I <sub>SM</sub>	Pulsed Source Current				180	1 A	integral reverse GV
	(Body Diode) ①⑤		100		p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_J = 25$ °C, $I_S = 28A$ , $V_{GS} = 0V$ ④	
t <sub>rr</sub>	Reverse Recovery Time		210	320	ns	$T_J = 25^{\circ}C, I_F = 28A$	
Q <sub>rr</sub>	Reverse RecoveryCharge		1.7	2.6	μC	di/dt = 100A/ <i>µ</i> s ⊕ ⑤	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} $\mathbb{Q}$ $V_{DD}=25V, starting $T_J=25^\circ$C, $L=1.4mH$ \\ $R_G=25\Omega, I_{AS}=28A.$ (See Figure 12) \\ \end{tabular}$
- ③  $I_{SD} \le 28A$ , di/dt ≤ 460A/ $\mu$ s,  $V_{DD} \le V_{(BR)DSS}$ ,
- ④ Pulse width  $\leq$  300 $\mu$ s; duty cycle  $\leq$  2%.
- © Uses IRF3710 data and test conditions

<sup>\*\*</sup> When mounted on FR-4 board using minimum recommended footprint.
For recommended footprint and soldering techniques refer to application note #AN-994.

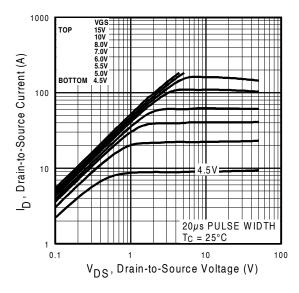


Fig 1. Typical Output Characteristics

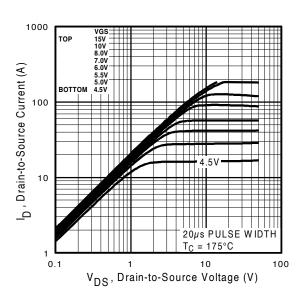


Fig 2. Typical Output Characteristics

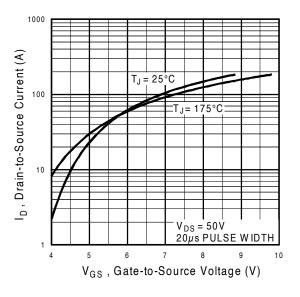
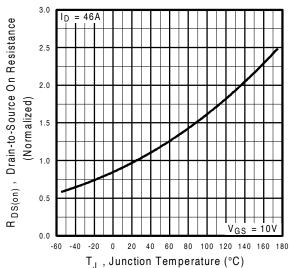
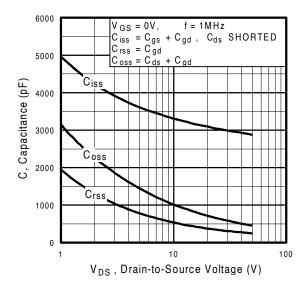


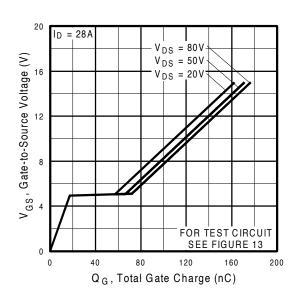
Fig 3. Typical Transfer Characteristics



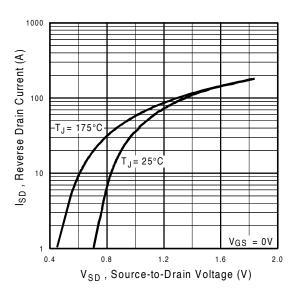
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

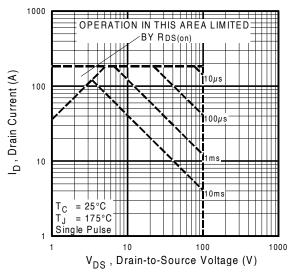
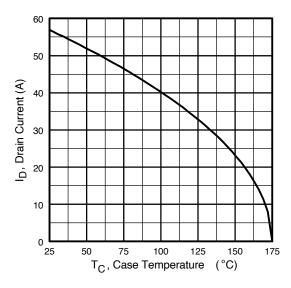


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

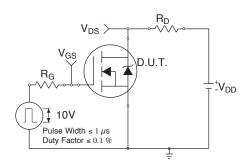


Fig 10a. Switching Time Test Circuit

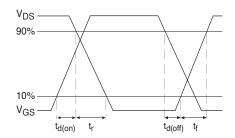


Fig 10b. Switching Time Waveforms

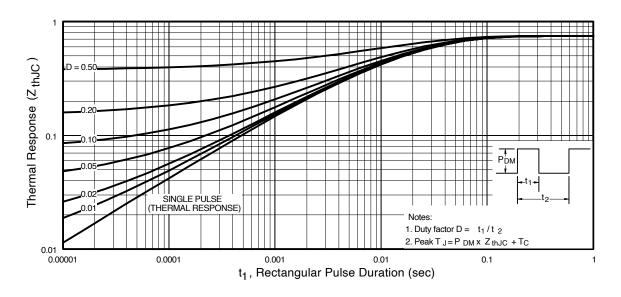


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

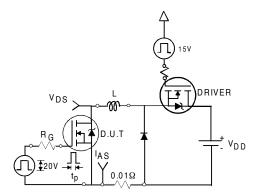


Fig 12a. Unclamped Inductive Test Circuit

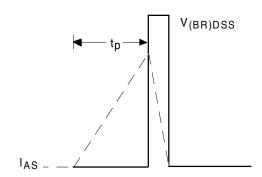


Fig 12b. Unclamped Inductive Waveforms

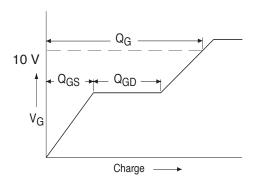
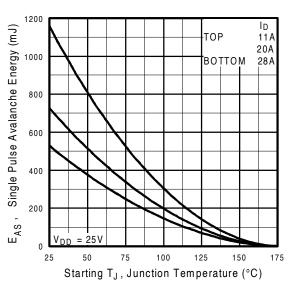


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

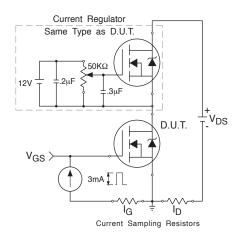
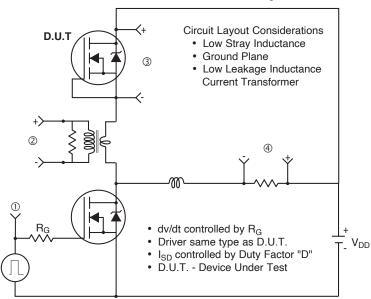


Fig 13b. Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



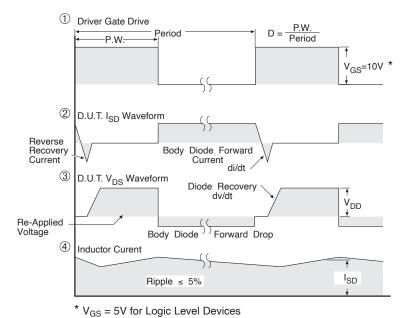
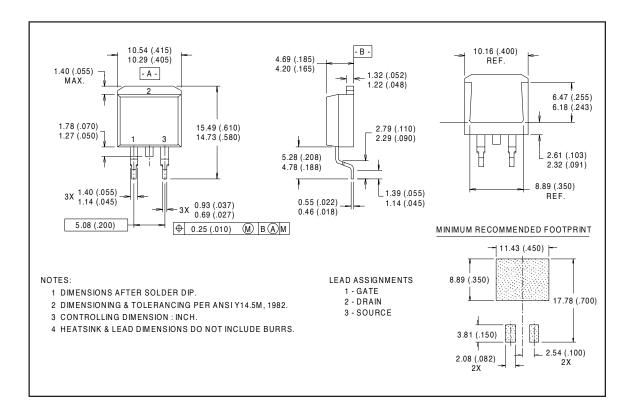
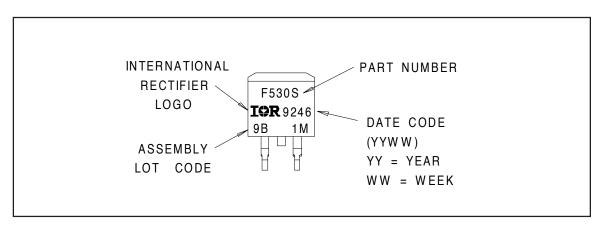


Fig 14. For N-Channel HEXFETS

## D<sup>2</sup>Pak Package Outline

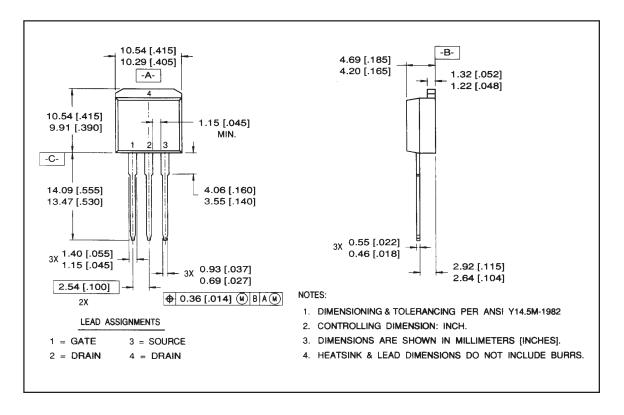


# Part Marking Information D<sup>2</sup>Pak

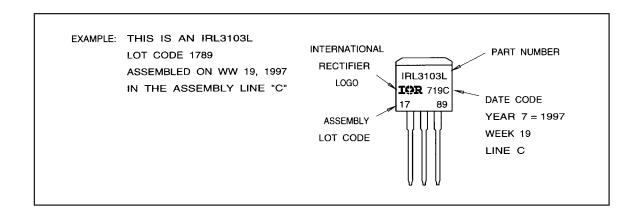


## Package Outline

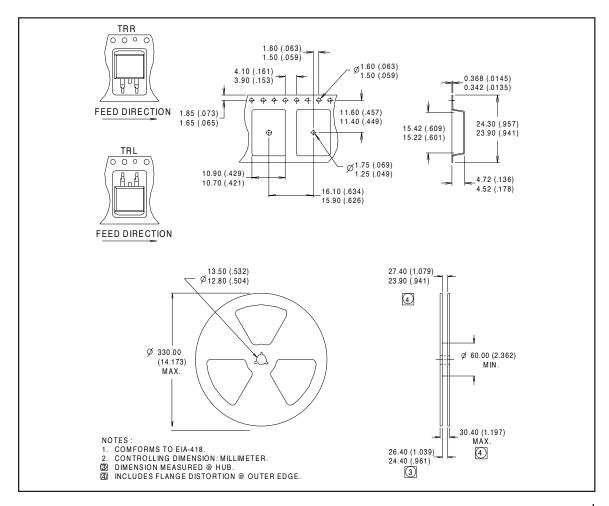
#### TO-262 Outline



# Part Marking Information TO-262



# Tape & Reel Information D<sup>2</sup>Pak



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